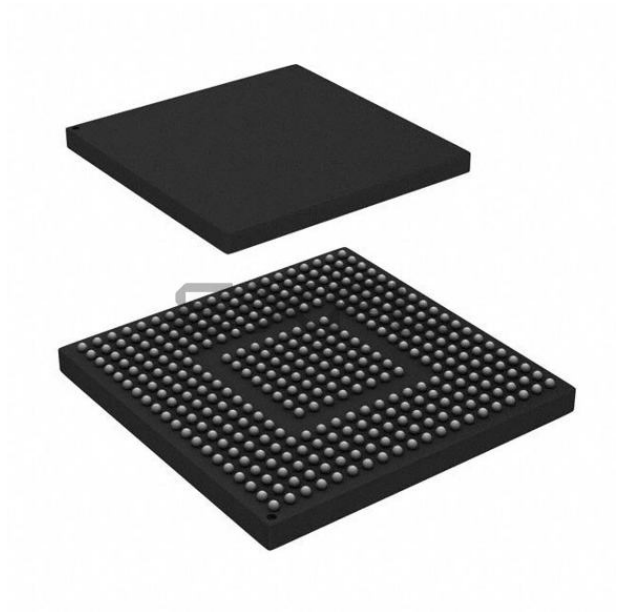

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	ARM® Cortex®-A5 + Cortex®-M4
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	400MHz, 167MHz
Co-Processors/DSP	Multimedia; NEON™ MPE
RAM Controllers	LPDDR2, DDR3, DRAM
Graphics Acceleration	Yes
Display & Interface Controllers	DCU, GPU, LCD, VideoADC, VIU
Ethernet	10/100Mbps (2)
SATA	-
USB	USB 2.0 OTG + PHY (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 85°C (TA)
Security Features	-
Package / Case	364-LFBGA
Supplier Device Package	364-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mvf60nn151cmk40

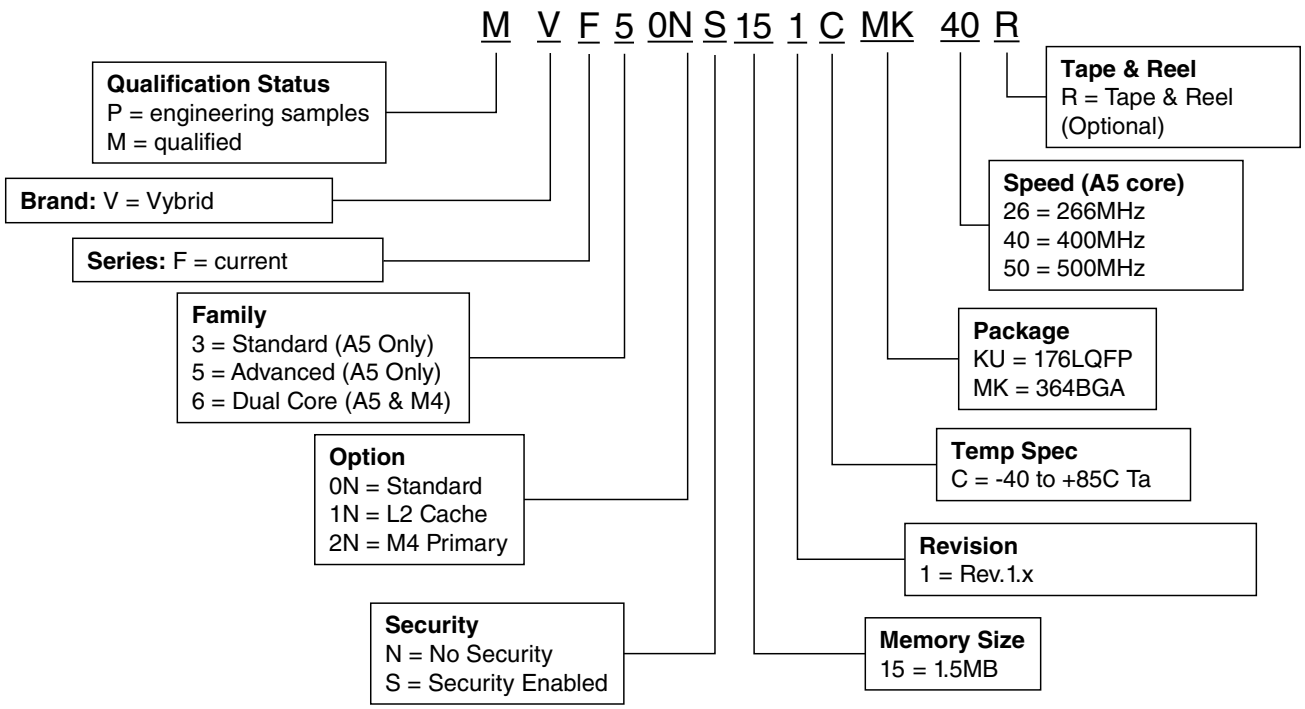


Figure 1. Part Number Format

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	• P = Engineering samples • M = Qualified
B	Brand	• V = Vybrid
S	Series	• F = current
F	Family	• 3 = Standard (A5 Only) • 5 = Advanced (A5 Only) • 6 = Dual Core (A5 & M4)
O	Option	• 0N = Standard • 1N = L2 Cache • 2N = M4 Primary
S	Security	• N = No Security • S = Security Enabled
MM	Memory size	• 15 = 1.5 MB

Table continues on the next page...

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	—	7	pF

3.4 Definition: Rating

A *rating* is a minimum or maximum value of a technical characteristic that, if exceeded, may cause permanent chip failure:

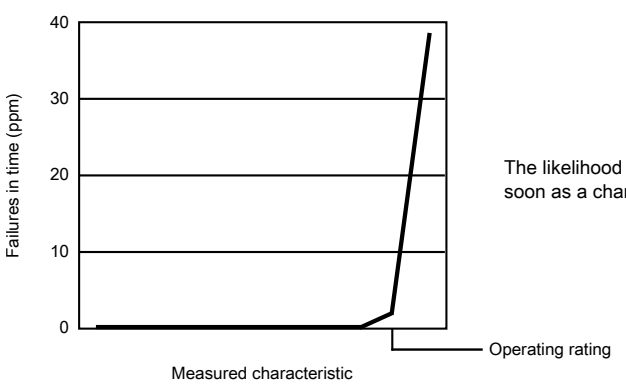
- *Operating ratings* apply during operation of the chip.
- *Handling ratings* apply when the chip is not powered.

3.4.1 Example

This is an example of an operating rating:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	–0.3	1.2	V

3.5 Result of exceeding a rating



The likelihood of permanent chip failure increases rapidly as soon as a characteristic begins to exceed one of its operating ratings.

6.2.1.5 External NPN Ballast

The internal main regulator requires an external NPN ballast transistor to be connected as shown in the following figure as well as an external capacitance to be connected to the device in order to provide a stable 1.2V digital supply to the device. The HPREG design allows for collector voltage lower than VDDREG value. See AN4807 at www.freescale.com .

NOTE

To not overload BCTRL output, collector voltage should appear no later than VDDREG / VDD33 (3.3V).

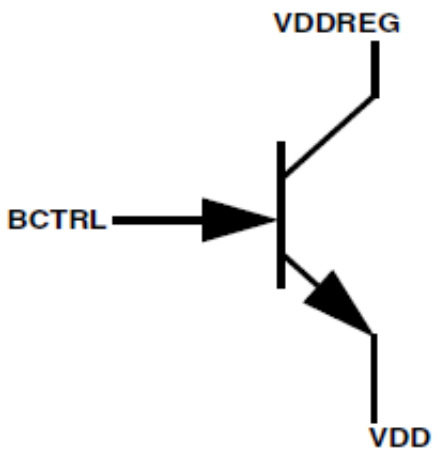


Figure 3. External NPN Ballast connections

Table 6. BCTRL OUTPUT specification

Parameter	Value	Comments
BCTRL OUTPUT specification	20mA	BCTRL driver can not drive more than 20mA current
Maximum pin voltage	VDDREG-0.5V	For Example, VDDREG =3.0V BCTRL should not exceed 2.5V.

Table 7. Assumptions For calculations

Parameter	Value
VDDREG	3.0V to 3.6V with typical value of 3.3V
Max DC Collector current	0.85A @85 °C
Emitter voltage	1.2V to 1.25V
Collector voltage	Equal to VDDREG

Table 8. General guidelines for selection of NPN ballast

Symbol	Parameters	Value	Unit	Comments
Hfe	Minimum DC current gain (Beta)	42.5		As BCTRL pin can not drive more than 20mA Minimum value of beta for a collector current of 0.85A comes out to be 42.5.
PD (Junction to ambient)	Minimum power dissipation @ TA=85 °C	2.04	W	Assuming 0.85A collector current with Collector voltage of Ballast 3.6V(max) we get VCE= 3.6V-1.2V=2.4V So power dissipated is 2.4V*0.85A=2.04W . This should be met for junction to ambient power dissipation spec of ballast
IcmaxDC peak	Maximum peak DC collector current	0.85	A	1.2A and above capacity device preferable
VBE	Maximum voltage that BCTRL pin can drive	1.25V for 0.85A @ 85 °C	V	For a VDDREG of 3.0 V (min.), BCTRL pin can drive voltage up to VDDREG - 0.5 V = 2.5 V. Since emitter of ballast is fixed at 1.25 V (max) if chosen ballast can supply 0.85 A collector current @ 85 °C with a base-to-emitter voltage of 1.25 V or lower, it is suitable for application.
Ft	Unity current gain Frequency of Ballast	50	MHz	

Reducing the collector-to-emitter voltage drop lowers the ballast transistor heat dissipation. This can be implemented in two ways:

1. By introducing series resistor or diode(s) between the collector and VDDREG (placed far enough from the transistor for proper cooling)
2. By connecting the collector to a separate lower-voltage supply

In both of the above cases the transistor has to stay away from the deep saturation region; otherwise, due to significant Hfe degradation, its base current exceeds the BCTRL output maximum value.

In general, the transistor must be selected such that its Vce saturation voltage is lower than the expected minimum Collector-Emitter voltage, and at the same time, the base current is less than 20 mA for the maximum expected collector current. More information can be found in collateral documentation at http://www.freescale.com

6.2.2 LVD electrical specifications

6.2.2.1 Main Supply electrical characteristics

Table 9. LVD_MAIN supply electrical characteristics

Main Supply LVD Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	
Upper voltage threshold (value @27°C)		2.76	2.915	V	
Lower voltage threshold (value @27°C)	2.656	2.73		V	
Time constant of RC filter at LVD input (0.69*RC)	3.3			µs	3.3 V noise rejection at LVD comparator input

6.2.2.2 LVD DIG characteristics

Table 10. LVD DIG electrical specifications [HPREG(RUN MODE) and LPREG(STOP MODE)]

LVD DIG Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	
Upper voltage threshold	1.135	1.16	1.185	V	
Lower voltage threshold	1.105	1.13	1.155	V	
Time constant of RC filter at LVD input	200			ns	1.2V noise rejection at the input of LVD comparator

Table 11. LVD DIG electrical specifications [ULPREG(STANDBY MODE)]

LVD DIG Parameters	Min	Typ	Max	Unit	Comments
Power supply	3.0	3.3	3.6	V	
Upper voltage threshold	1.105	1.13	1.155	V	
Lower voltage threshold	1.075	1.10	1.125	V	
Time constant of RC filter at LVD input	200			ns	1.2V noise rejection at the input of LVD comparator

6.2.3 LDO electrical specifications

6.2.3.1 LDO_1P1

Table 12. LDO_1P1 parameters

Specification	Min	Typ	Max	Unit	Comments
VDDIO	3	3.3	3.6	V	IO supply
VDD1P1_OUT	0.9	1.1	1.2	V	Regulator output
I_out	-		150	mA	>= 300mV drop out
Regulator output programming range	0.8	1.1	1.4	V	Programmable in 25mV steps
Brownout Voltage	0.85	0.94		V	
Brownout offset step	0	-	175	mV	Programmable in 25mV steps
Minimum external decoupling capacitor	1	-	-	µF	low ESR

For additional information, see the device reference manual.

6.2.3.2 LDO_2P5

Table 13. LDO_2P5 parameters

Specification	Min	Typ	Max	Unit	Comments
VDDIO	3	3.3	3.6	V	IO supply
VDD2P5_OUT	2.3	2.5	2.6	V	Regulator output
I_out	-		350	mA	@500mV drop out
Regulator output programming range	2.0	2.5	2.75	V	Programmable in 25mV steps
[P:][C:] Brownout Voltage	2.25	2.33		V	
Brownout offset step	0	-	175	mV	Programmable in 25mV steps
Minimum external decoupling capacitor	1	-	-	µF	low ESR

For additional information, see the reference manual.

Table 35. VideoADC Specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{BG}	Bandgap voltage	—	0.6	—	V	Bandgap voltage on VADC_AFE_BANDGAP pin. Pin should be decoupled with a 100nF capacitor

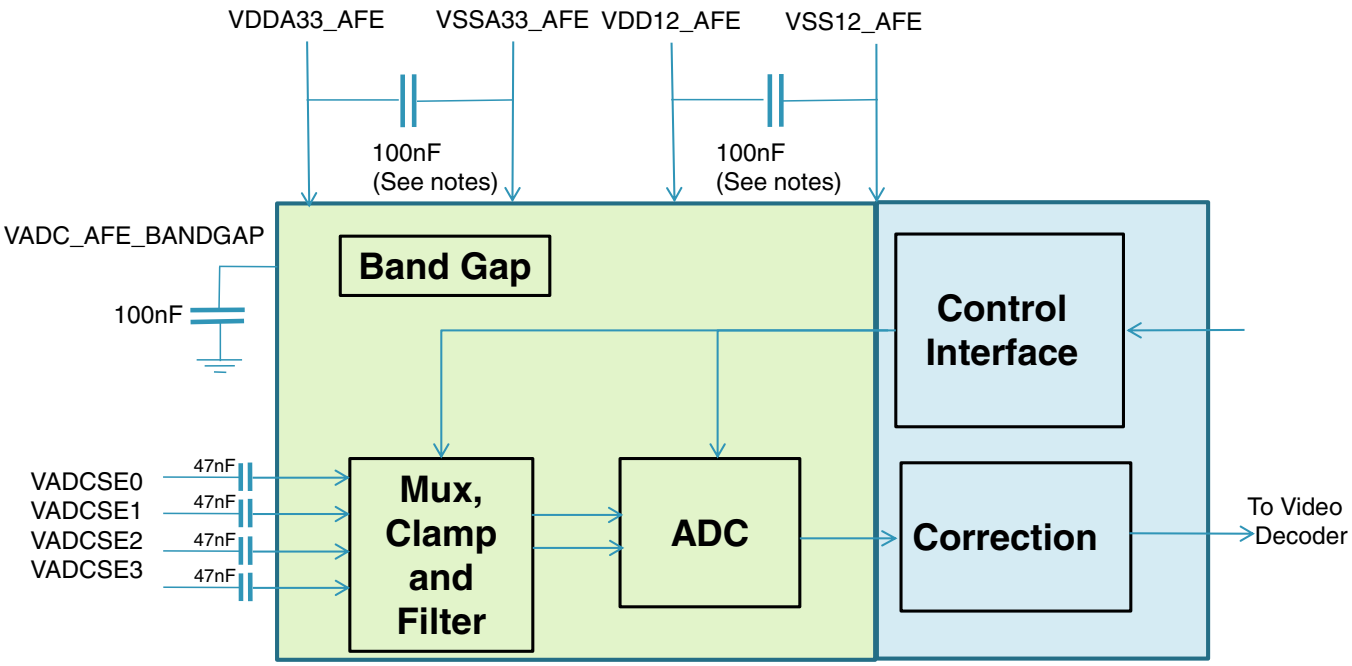


Figure 12. VideoADC supply scheme

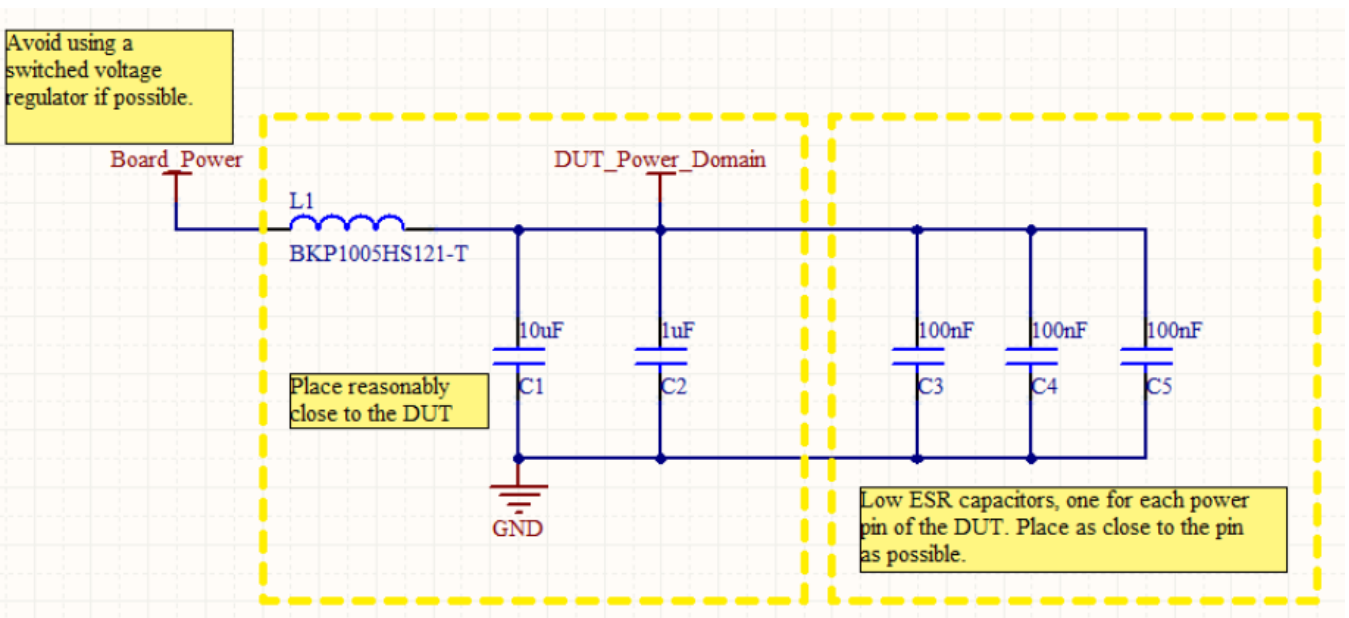


Figure 13. VideoADC supply decoupling

NOTE

VideoADC 3.3V and 1.2V power supply pins should be decoupled to their respective grounds using low-ESR 100nF capacitors

NOTE

If possible, avoid using switched voltage regulators for the AFE power domains. Use linear voltage regulators instead.

NOTE

The 3.3V and 1.2V power domains should be separated from other circuitry on the board by inductors/beads to filter out high frequency noise.

9.2 Display and Video interfaces

9.2.1 DCU Switching Specifications

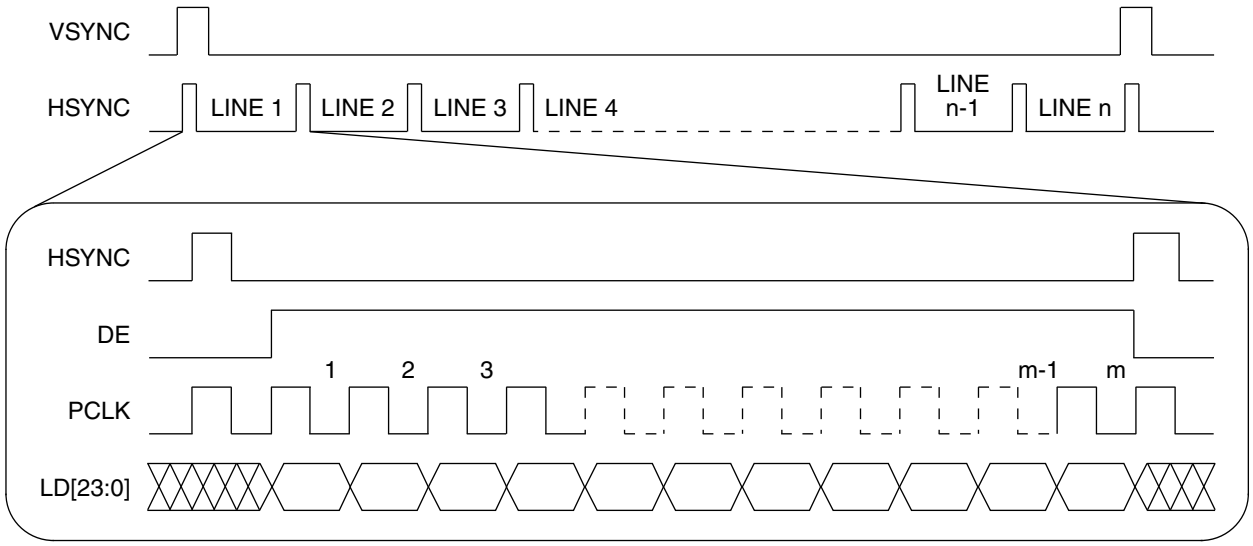
9.2.1.1 Interface to TFT panels (DCU0/1)

This section provides the LCD interface timing for a generic active matrix color TFT panel. In the figure below, signals are shown with positive polarity. The sequence of events for active matrix interface timing:

- PCLK latches data into the panel on its positive edge (when positive polarity is selected). In active mode, PCLK runs continuously. This signal frequency could be from 5 to 66 MHz depending on the panel type.
- HSYNC causes the panel to start a new line. It always encompasses at least one PCLK pulse.
- VSYNC causes the panel to start a new frame. It always encompasses at least one HSYNC pulse.
- DE acts like an output enable signal to the LCD panel. This output enables the data to be shifted onto the display. When disabled, the data is invalid and the trace is off.

Figure 14. TFT LCD interface timing overview[1]

1. In the figure, LD[23:0]" signal is "line data," an aggregation of the DCU's RGB signals—R[0:7], G[0:7] and B[0:7].



9.2.1.2 Interface to TFT LCD Panels—Pixel Level Timings

This section provides the horizontal timing (timing of one line), including both the horizontal sync pulse and data. All parameters shown in the figure below are programmable. This timing diagram corresponds to positive polarity of the PCLK signal (meaning the data and sync signals change on the rising edge) and active-high polarity of the HSYNC, VSYNC and DE signals. The user can select the polarity of the HSYNC and VSYNC signals via the SYN_POL register, whether active-high or active-low. The default is active-high. The DE signal is always active-high. Pixel clock inversion and a flexible programmable pixel clock delay are also supported. They are programmed via the clock divide . The DELTA_X and DELTA_Y parameters are programmed via the DISP_SIZE register. The PW_H, BP_H and FP_H parameters are programmed via the HSYN PARA register. The PW_V, BP_V and FP_V parameters are programmed via the VSYN_PARA register.

Table 36. LCD interface timing parameters—horizontal and vertical

Symbol	Characteristic		Unit
t_{PCP}	Display pixel clock period	11.2	ns
t_{PWH}	HSYNC pulse width	PW_H * t_{PCP}	ns
t_{BPH}	HSYNC back porch width	BP_H * t_{PCP}	ns
t_{FPH}	HSYNC front porch width	FP_H * t_{PCP}	ns
t_{SW}	Screen width	DELTA_X * t_{PCP}	ns
t_{HSP}	HSYNC (line) period	(PW_H + BP_H + FP_H + DELTA_X) * t_{PCP}	ns
t_{PWV}	VSYNC pulse width	PWV * t_{HSP}	ns
t_{BPV}	VSYNC back porch width	BP_V * t_{HSP}	ns
t_{FPV}	VSYNC front porch width	FP_V * t_{HSP}	ns
t_{SH}	Screen height	DELTA_Y * t_{HSP}	ns
t_{VSP}	VSYNC (frame) period	(PW_V + BP_V + FP_V + DELTA_Y) * t_{HSP}	ns

9.4 Audio interfaces

9.4.1 Enhanced Serial Audio Interface (ESAI) Timing Parameters

The ESAI consists of independent transmitter and receiver sections, each section with its own clock generator. The following table shows the interface timing values.

Table 44. Enhanced Serial Audio Interface (ESAI) Timing

No	Characteristics	Symbol	Min	Max	Condition[1]	Unit
1	Clock cycle[2]	t_{SSICC}	30.0 (4 × T_c)	— —	master	ns
2	Clock high period: • master • slave	— —	6 (2 × T_c – 9.0) 15 (2 × T_c)	— —	— —	ns
3	Clock low period: • master • slave	— —	6 (2 × T_c – 9.0) 15 (2 × T_c)	— —	— —	ns
4	FSR Input and Data Input setup time before SCKR (SCK in synchronous mode) falling edge	— —	6 15	— —	Slave Master	ns
5	FSR Input and Data Input hold time after SCKR falling edge	— —	2 0	— —	Slave Master	ns
6	SCKT rising edge to FST out and Data out valid	— —	— —	15 6	Slave Master	ns
7	SCKT rising edge to FST out and Data out hold	— —	— —	0 0	Slave Master	ns
8	FST input setup time before SCKT falling edge	— —	6 15	— —	Slave Master	ns
9	FST input hold time after SCKT falling edge	— —	2 0	— —	Slave Master	ns
10	HCKR/HCKT clock cycle	—	15 (2 x T_C)	—	—	ns
11	HCKT input rising edge to SCKT output	—	—	18.0	—	ns
12	HCKR input rising edge to SCKR output	—	—	18.0	—	ns

1. SCKT(SCKT pin) = transmit clock SCKR(SCKR pin) = receive clock FST(FST pin) = transmit frame sync FSR(FSR pin) = receive frame sync HCKT(HCKT pin) = transmit high frequency clock HCKR(HCKR pin) = receive high frequency clock
2. For the internal clock, the external clock cycle is defined by Icyc and the ESAI control register.

9.5 Memory interfaces

9.5.1 QuadSPI timing

- All data is based on a negative edge data launch from the device and a negative edge data capture, as shown in the timing diagrams in this section. This corresponds to the N/1 sample point as shown in the reference manual QSPI section "Internal Sampling of Serial Flash Input Data."
- Measurements are with a load of 35 pF on output pins. I/P Slew : 1ns
- Timings assume a setting of 0x0000_000x for QSPI_SMPR register (see the reference manual for details).

SDR mode

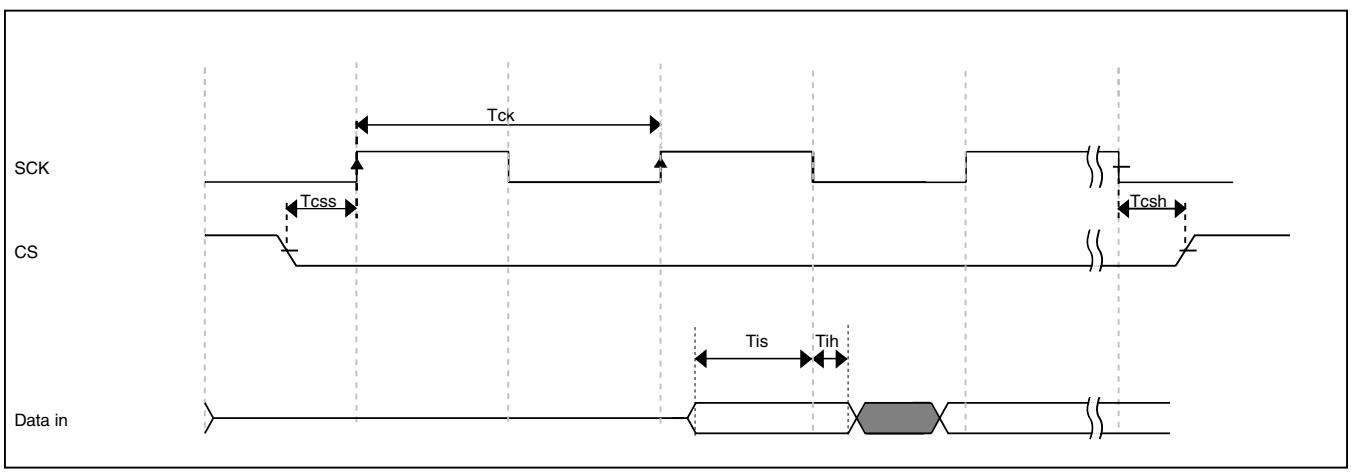


Figure 30. QuadSPI Input/Read timing (SDR mode)

Table 48. QuadSPI Input/Read timing (SDR mode)

Symbol	Parameter	Value		Unit
		Min	Max	
T_{is}	Setup time for incoming data	4.5	—	ns
T_{ih}	Hold time requirement for incoming data	0	—	ns

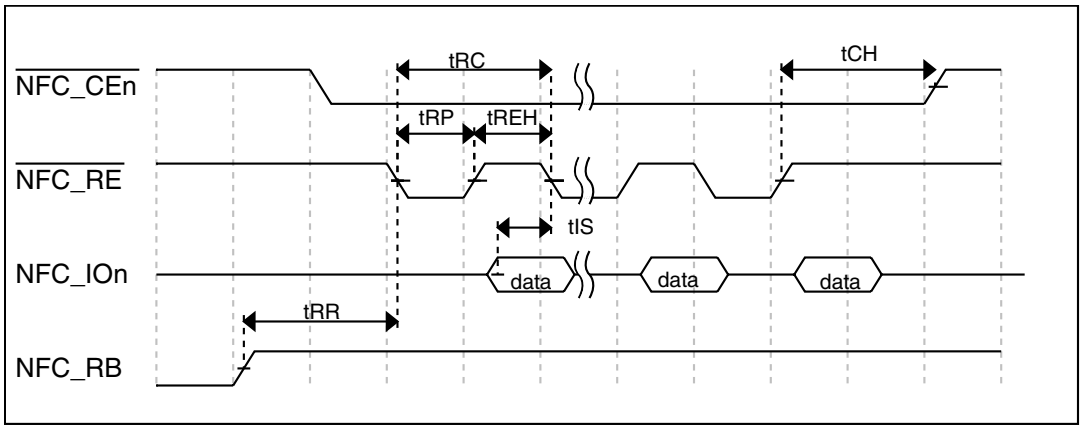


Figure 38. Read data latch cycle timing in fast mode

9.5.3 FlexBus timing specifications

This section provides FlexBus timing parameters. All processor bus timings are synchronous; input setup/hold and output delay are given in respect to the rising edge of a reference clock, FB_CLK. The FB_CLK frequency may be the same as the internal system bus frequency.

The following timing numbers indicate when data is latched or driven onto the external bus, relative to the FlexBus output clock (FB_CLK). All other timing relationships can be derived from these values.

All FlexBus signals use pad type pad_fsr. The following timing specifications assume a pad slew rate setting of 11 and a load of 50 pF[3]

Table 53. FlexBus timing specifications

Num	Characteristic	Min	Max	Unit
	Frequency of operation	—	83[1] (with Wait state)	MHz
			57[2] without Wait state , -1	
FB1	Clock Period	12	—	ns
FB4	Input setup	10.6	—	ns
FB5	Input hold	0	—	ns
FB2	Output valid	—	6.4	ns
FB3	Output hold	0	—	ns

1. Freq = 1000/(11+ access time of external memory+ trace delay for clk and data)
2. Freq = 1000/(17+access time of external memory)

3. These timing parameters are specified assuming maximum operating frequency and the fastest pad slew rate setting (11).

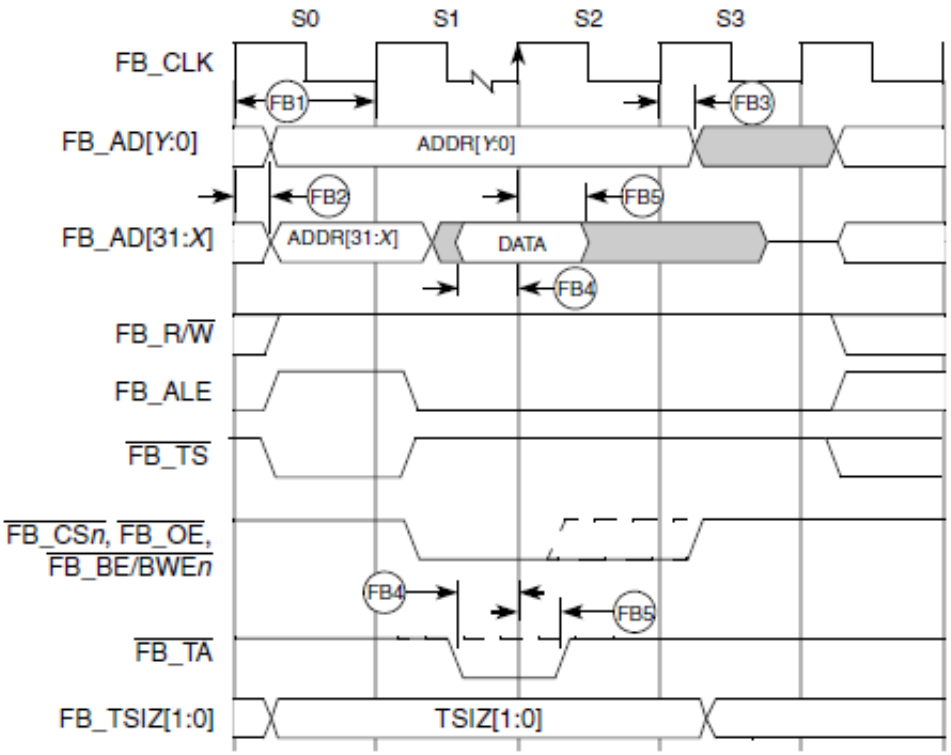


Figure 39. FlexBus read timing

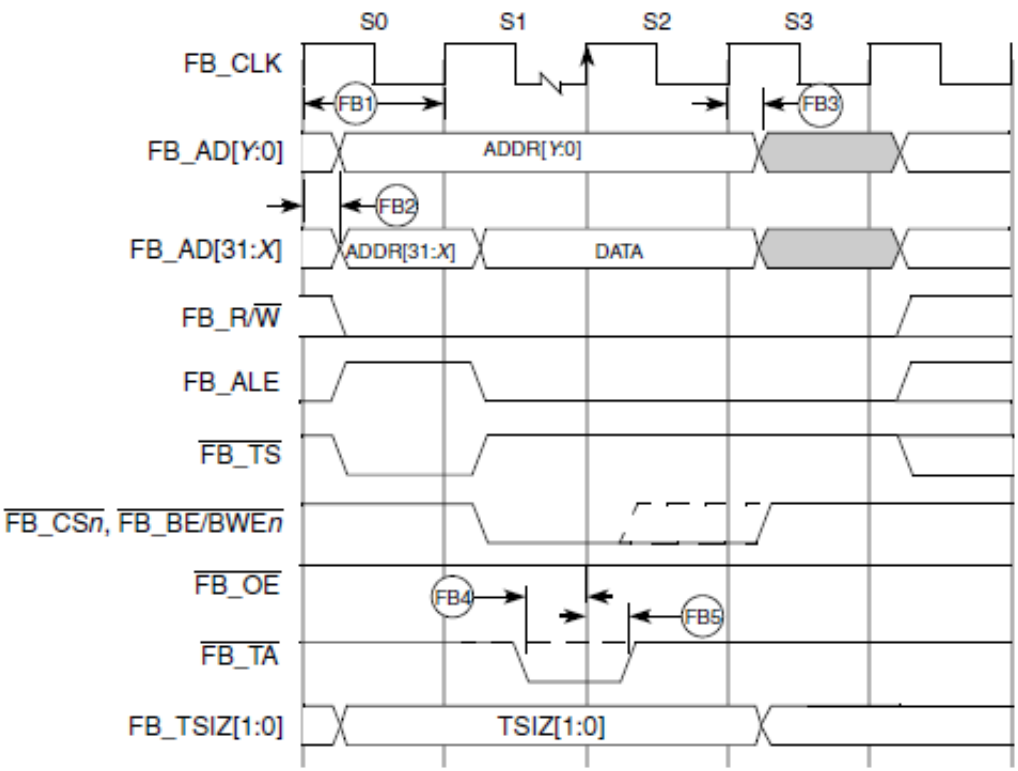


Figure 40. FlexBus write timing

NOTE

RESET pin has a external weak pull UP requirement if DDR3 memory is required to support content retention in the device low power modes where core voltage is off but DRAM voltage is on.

NOTE

CKE pin has a external weak pull down requirement.

Table 54. DDR3 Timing Parameter

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
DDR1	CK clock high-level width	tCH	0.47	0.53	tCK
DDR2	CK clock low-level width	tCL	0.47	0.53	tCK
DDR4	CS, RAS, CAS, CKE, WE, ODT setup time	tIS	440	-	ps
DDR5	CS, RAS, CAS, CKE, WE, ODT hold time	tIH	315	-	ps
DDR6	Address output setup time	tIS	440	-	ps
DDR7	Address output hold time	tIH	315	-	ps

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF.

9.5.4.2 DDR3 Read Cycle

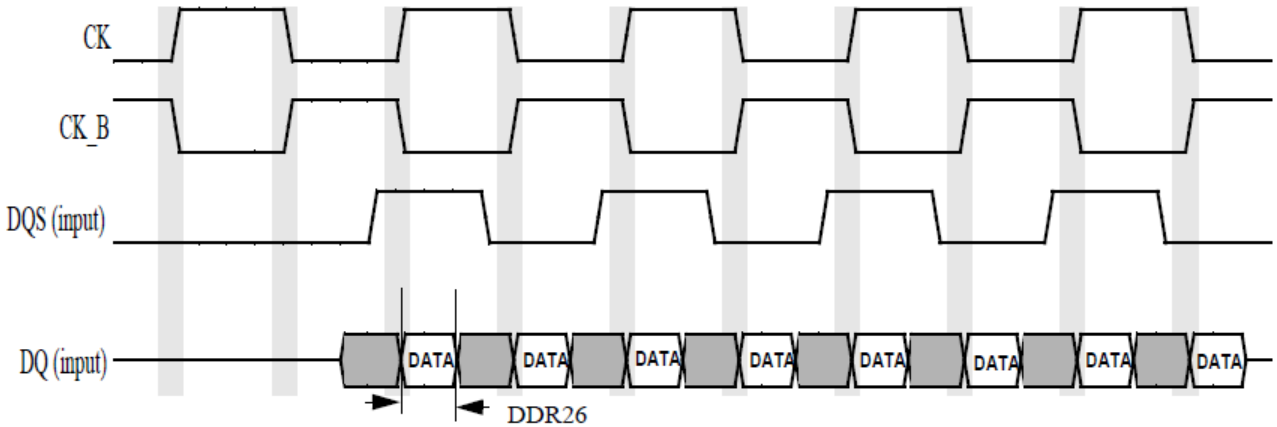


Figure 42. DDR3 Read Cycle

Table 55. DDR3 Read Cycle

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
DDR26	Minimum required DQ valid window width	-	750	-	ps

NOTE

To receive the reported setup and hold values, read calibration should be performed in order to locate the DQS in the middle of DQ window.

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF

9.5.4.6 LPDDR2 Write Cycle

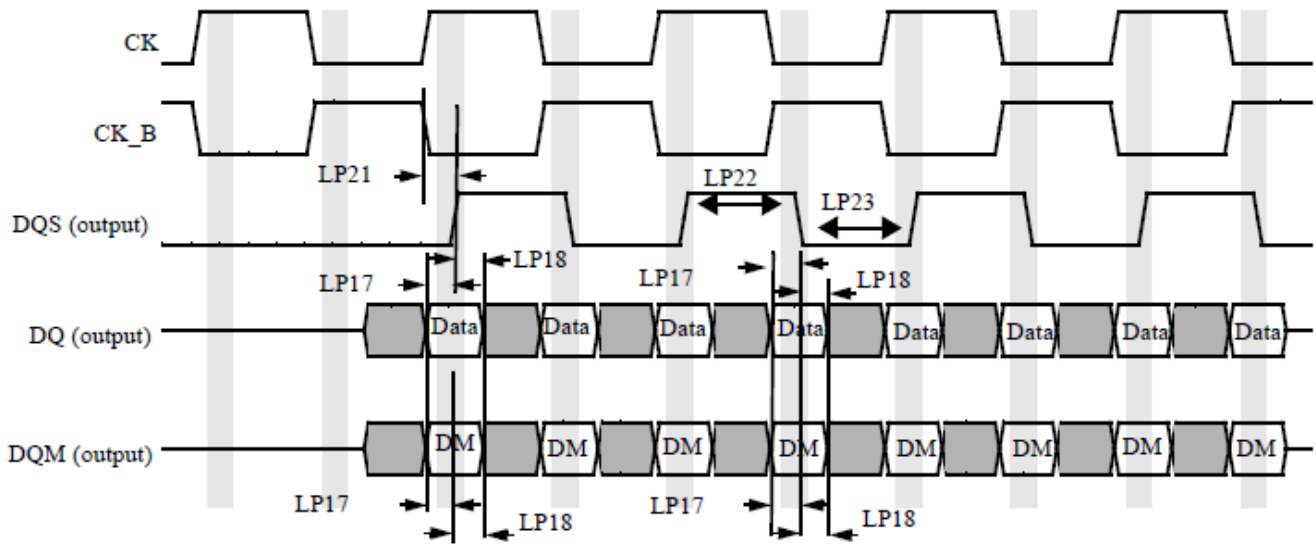


Figure 46. LPDDR3 Write Cycle

Table 59. LPDDR2 Write Cycle

ID	Parameter	Symbol	CK = 400 MHz		Unit
			Min	Max	
LP17	DQ and DQM setup time to DQS (differential strobe)	tDS	220	0.55	ps
LP18	DQ and DQM hold time to DQS (differential strobe)	tDH	220	0.55	ps
LP21	DQS latching rising transitions to associated clock edges	tDQSS	-0.25	+0.25	tCK
LP22	DQS high level width	tDQSH	0.4	-	tCK
LP23	DQS low level width	tDQSL	0.4	-	tCK

NOTE

To receive the reported setup and hold values, write calibration should be performed in order to locate the DQS in the middle of DQ window.

NOTE

All measurements are in reference to Vref level.

NOTE

Measurements were done using balanced load and 25 ohms resistor from outputs to VDD_REF.

Table 61. I2C input timing specifications — SCL and SDA[1] (continued)

No.	Parameter	Min.	Max.	Unit
3	Bus free time between Start and Stop condition	4.7	—	µs
4	Data hold time	0.0	—	µs
5	Clock high time	4	—	PER_CLK Cycle
6	Data setup time	0.0	—	ns
7	Start condition setup time (for repeated start condition only)	2	—	PER_CLK Cycle
8	Stop condition setup time	2	—	PER_CLKCycle

1. I2C input timing is valid for Automotive and TTL inputs levels, hysteresis enabled, and an input edge rate no slower than 1 ns (10% – 90%).
2. PER_CLK is the IPG Clock which drive the I2C BIU and module clock inputs. Typically this is 83Mhz. See the Clocking Overview chapter in the device reference manual for more details.

Table 62. I2C output timing specifications — SCL and SDA[1234]

No.	Parameter	Min	Max	Unit
1	Start condition hold time	6	—	PER_CLK Cycle[5]
2	Clock low time	10	—	PER_CLK Cycle
3	Bus free time between Start and Stop condition	4.7	—	µs
4	Data hold time	7	—	PER_CLK Cycle
5	Clock high time	10	—	PER_CLK Cycle
6	Data setup time	2	—	PER_CLK Cycle
7	Start condition setup time (for repeated start condition only)	20	—	PER_CLK Cycle
8	Stop condition setup time	10	—	PER_CLK Cycle

1. All output timing is worst case and includes the mismatching of rise and fall times of the output pads.
2. Output parameters are valid for CL = 25 pF, where CL is the external load to the device (lumped). The internal package capacitance is accounted for, and does not need to be subtracted from the 25 pF value.
3. Timing is guaranteed to same drive capabilities for all signals, mixing of pad drives may reduce operating speedsand may cause incorrect operation.
4. Programming the IBFD register (I2C bus Frequency Divider) with the maximum frequency results in the minimum output timings listed. The I2C interface is designed to scale the data transition time, moving it to the middle of the SCL low period. The actual position is affected by the pre-scale and division values programmed in the IBC field of the IBFD register.
5. PER_CLK is the IPG Clock which drive the I2C BIU and module clock inputs. Typically this is 83Mhz. See the Clocking Overview chapter in the device reference manual for more details.

364 MAP BGA	176 LQFP	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
B3	24	VSS			VSS							
B5	32	VSS			VSS							
B8	—	VSS			VSS							
B11	—	VSS			VSS							
B13	—	VSS			VSS							
B16	—	VSS			VSS							
B19	—	VSS			VSS							
C2	—	VSS			VSS							
D17	—	VSS			VSS							
E5	—	VSS			VSS							
E8	—	VSS			VSS							
E11	—	VSS			VSS							
E14	—	VSS			VSS							
E19	—	VSS			VSS							
F2	—	VSS			VSS							
G17	—	VSS			VSS							
H4	—	VSS			VSS							
J2	—	VSS			VSS							
J18	—	VSS			VSS							
M2	—	VSS			VSS							
M4	—	VSS			VSS							
M18	—	VSS			VSS							
R2	—	VSS			VSS							
R18	—	VSS			VSS							
U7	—	VSS			VSS							
U19	—	VSS			VSS							
V13	—	VSS			VSS							
W6	—	VSS			VSS							
V17	—	VSS			VSS							
Y1	—	VSS			VSS							
Y20	—	VSS			VSS							
H19	—	VSS			VSS							
L19	—	VSS			VSS							
P19	—	VSS			VSS							
J5	—	SDRAMC_ VDD2P5			SDRAMC_ VDD2P5							
E6	—	SDRAMC_ VDD2P5			SDRAMC_ VDD2P5							
E10	—	SDRAMC_ VDD2P5			SDRAMC_ VDD2P5							

Table 79. Revision History

Rev. No.	Date	Substantial Changes
		Added Part Number Format figure Updated the Fields table as per the device part numbers Added Part Numbers table Added External NPN Ballast section In the LVD Dig Electrical Specs, minimum value of Upper Voltage Threshold and Lower Voltage threshold In the FlexBus timing specifications table, clarified the Frequency of operation In the Power consumption, filled TBDs. Updated footnotes Rewritten the EMC radiated emissions operating behaviors table In the GPIO DC Electrical characteristics table: • Vhys test condition changed • Added R_Keeper row In the DDR operating conditions, changed the Vddi Min and Max values In the Power sequencing table, rremoved some rows In the Power Supply section, removed LVDS and removed the note In the Recommended operating conditions table, updated min and max of VDD12_AFE and FA_VDD. Updated Min, Max, and Typ for VDD Added the Recommended Connections for Unused Analog Interfaces table In the 12-bit ADC Characteristics table, updated the typ and max values of TUE, DNL. INL, ZSE, FSE Added Receive and Transmit signal timing specifications for MII interfaces In the DSPI table, clarified the TBDs In PLL 4, PLL 5, PLL 6 electrical characteristics tables, added footnotes In the JTAG electrical table, clarified the TBDs In the pinouts section, added Special Signal table Added Power Supply pins section Added Functional Assignment section

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